

RADLAS 2024 : 6th Workshop on Laser Testing of Radiation Effects on Components and Systems

Wednesday, 11 September 2024

Session: Recent Laser test results - Newton 2 (10:10 - 11:10)

time	[id] title	presenter
10:10	[24] SEE Laser testing at ESA	BOREL, Thomas
10:30	[12] Exploration of the Single Event Effect Sensitivity of a 16nm FinFET System-on-Chip using Single-Photon Absorption Laser Testing	Mr FONGRAL, Matthieu
10:50	[14] Single-Event Effects Laser Testing of a 7nm FinFET System-on-Chip with AI-Acceleration Capabilities	ACHAQ, salma

Session: Recent Laser test results - Newton 2 (11:40 - 12:20)

time	[id] title	presenter
11:40	[23] Pulsed-Laser Single-Event Effects in Wide Bandgap Semiconductor Devices	Dr KHACHATRIAN, Ani
12:00	[11] Laser Fault Injection on power off devices	GRANDAMME, Paul